

9/23/03

SHEET 1 OF 2

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243028US0DIV		SERIAL NO. NEW APPLICATION	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Toshimitsu TETSUI, et al.			
				FILING DATE HEREWITH		GROUP 1742	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
jm	AA	5,226,985	07-13-93	Y-W. KIM et al.			
jm	AB	5,558,729	09-24-96	Y-W. KIM, et al.			
jm	AC	5,442,847	08-22-95	S.L. SEMIATIN, et al.			
jm	AD	5,846,351	12-08-98	N. MASAHASHI, et al.			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
jm	AO	64-042539	02-14-89	JAPAN		X	
jm	AP	1-298127	12-01-89	JAPAN		X	
jm	AQ	6-049565	02-22-94	JAPAN		X	
jm	AR	6-041661	02-15-94	JAPAN		X	
	AS	62-000215	01-06-87	JAPAN		X	
jm	AT	4-066630	03-03-92	JAPAN		X	
jm	AU	4-124236	04-24-92	JAPAN		X	
jm	AV	6-49624	02-22-94	JAPAN		X	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
jm	AW	D. ZHANG et al., Intermetallics, Vol. 7, No. 10, XP-004177382, pps. 1081-1087, "Characterization of Controlled Microstructures in A TiAl (Cr, Mo, Si, B) ALLOY," October 1999.					
jm	AX	"ASM Handbook: Vol. 3 Alloy Phase Diagrams," ASM International, 1992, p. 254.					
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>jm</i>					Date Considered 10/12/05		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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	AH						
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	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
jm	AO	WO 96/30551	10-03-96	WIPO			
jm	AP	1-259139	10-16-89	JAPAN			X
jm	AQ	43 18 424	12-08-94	GERMANY			X
jm	AR	6-340955	12-13-94	JAPAN			X
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>jm</i>					Date Considered 10/12/05		
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12/23/03



LIST OF RELATED CASES

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
230230US0	10/286,854	11/04/02	TETSUI
243028US0 DIV*	10/667,651	09/23/03	TETSUI, et al.

The serial numbers above have been considered by the examiner but are crossed out as they will not be printed in the references cited section.

*Present Application; listed for information
NFO/tas

Jim M 10/12/05